

Merging Integrated Photonics and Electron Beams: μeV-Electron-Spectroscopy and Single-Particle Heralding

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Motivation

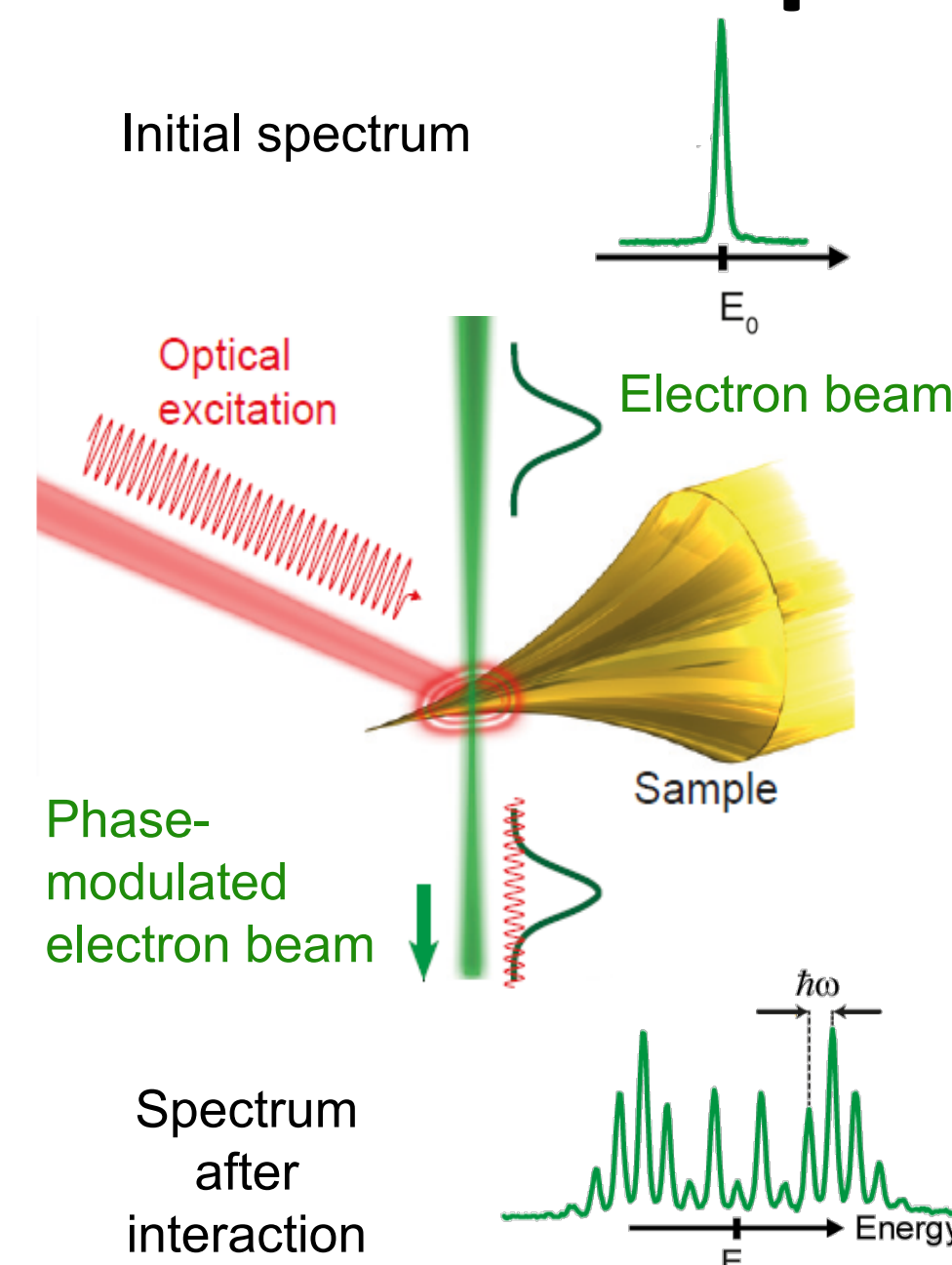
Electron microscopy provides unique insights into heterogeneous nanomaterials and integrated circuits^[1,2], but it does not yet harness many advanced capabilities from photon science, including programmable optics, coherent spectroscopy, or quantum-enhanced imaging.

Merging these two realms defines a new frontier in nanometrology and promises a novel class of light-enhanced electron microscopes^[3,4]. However, this requires concepts and technology to interact and detect electrons and photons at the single-particle level.

Here, we present the coupling and manipulation of electron beams with light at an unprecedented efficiency using integrated photonics^[5-7]. These advances may contribute to the in-situ metrology of functional silicon photonic devices.

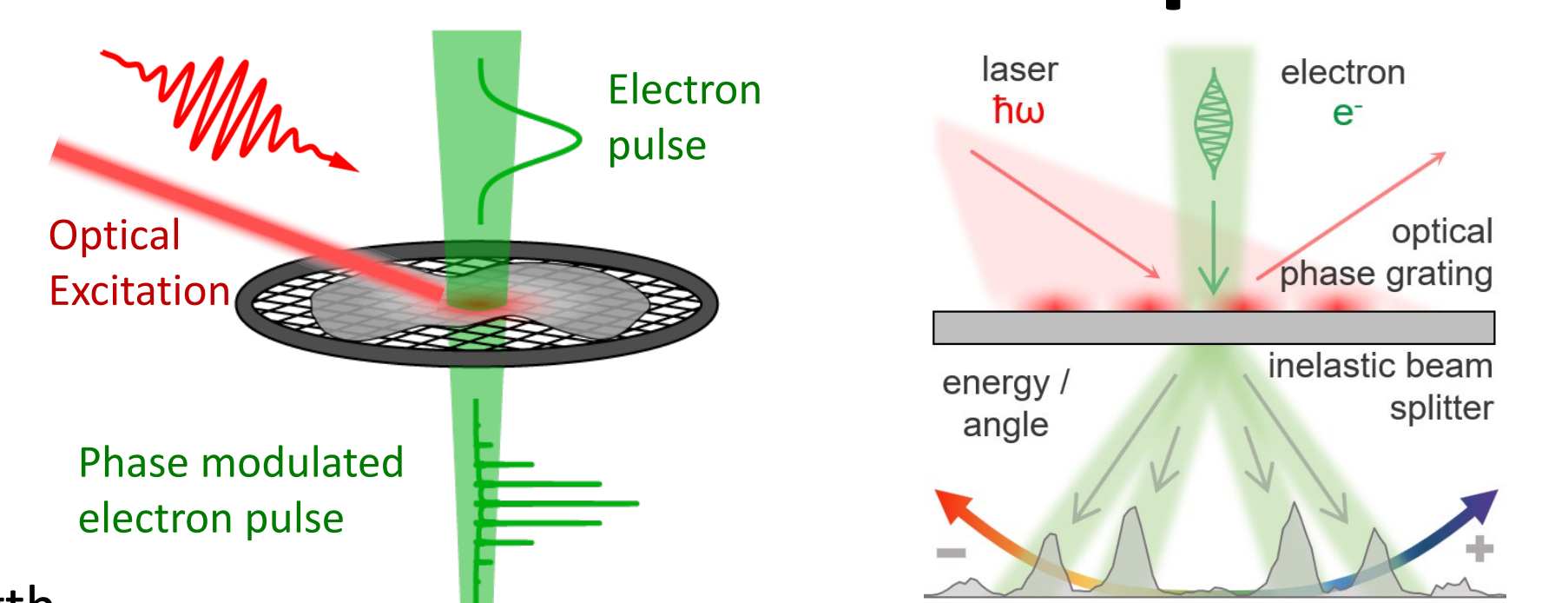


Coherent Optical Phase Modulation & Laser-Driven Electron Optics



- Absorption and emission of photons in intense optical near-fields^[8,9]
→ Formation of energy sidebands
- Final electron state:
 $|\Psi_f\rangle = \sum_N J_N(2|g|) e^{i \arg(g)} |E_0 + N\hbar\omega\rangle$
depends on electron-light coupling strength
 $g(R, \omega) = \frac{e}{2\hbar\omega} \int_{\mathbb{R}} E_z(R, z, \omega) e^{i \frac{\omega}{v} z} dz$

Electron-light interaction is typically weak, required intense optical pulses



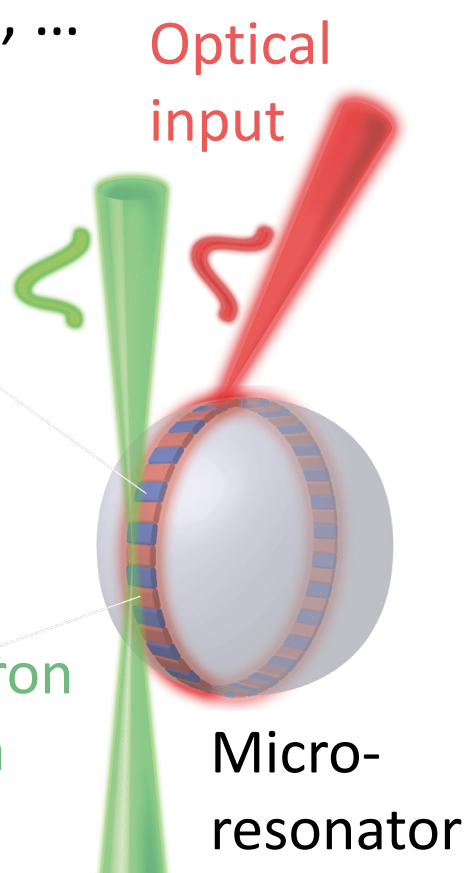
coherent optical phase modulation in space & time^[10,11]

$$\varphi(z, x) = -2i|g| \sin\left(\frac{\omega}{v_e} z + k_{\parallel} x + \varphi_0\right)$$

→ Aberration correction, beam chopping & dose control, beam splitters & phase plates, ...

enhancing the interaction^[5]

- Resonant cavity field enhancement
- Electron-light velocity phase matching



Integrated Photonics Platform for Efficient Electron-Light Coupling

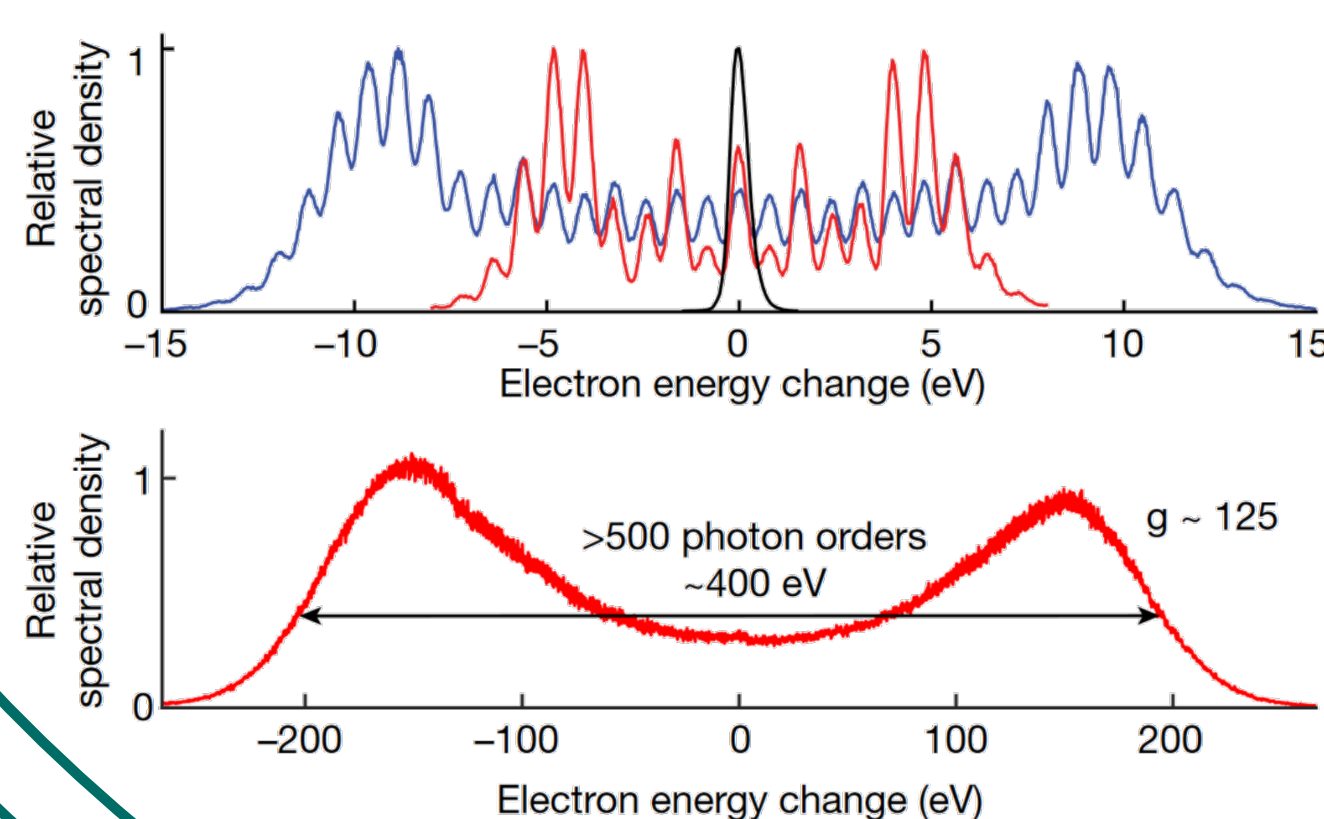
Electron beam properties^[4]

- Nanometer spatial resolution
- Sub-eV energy spread in initial beam

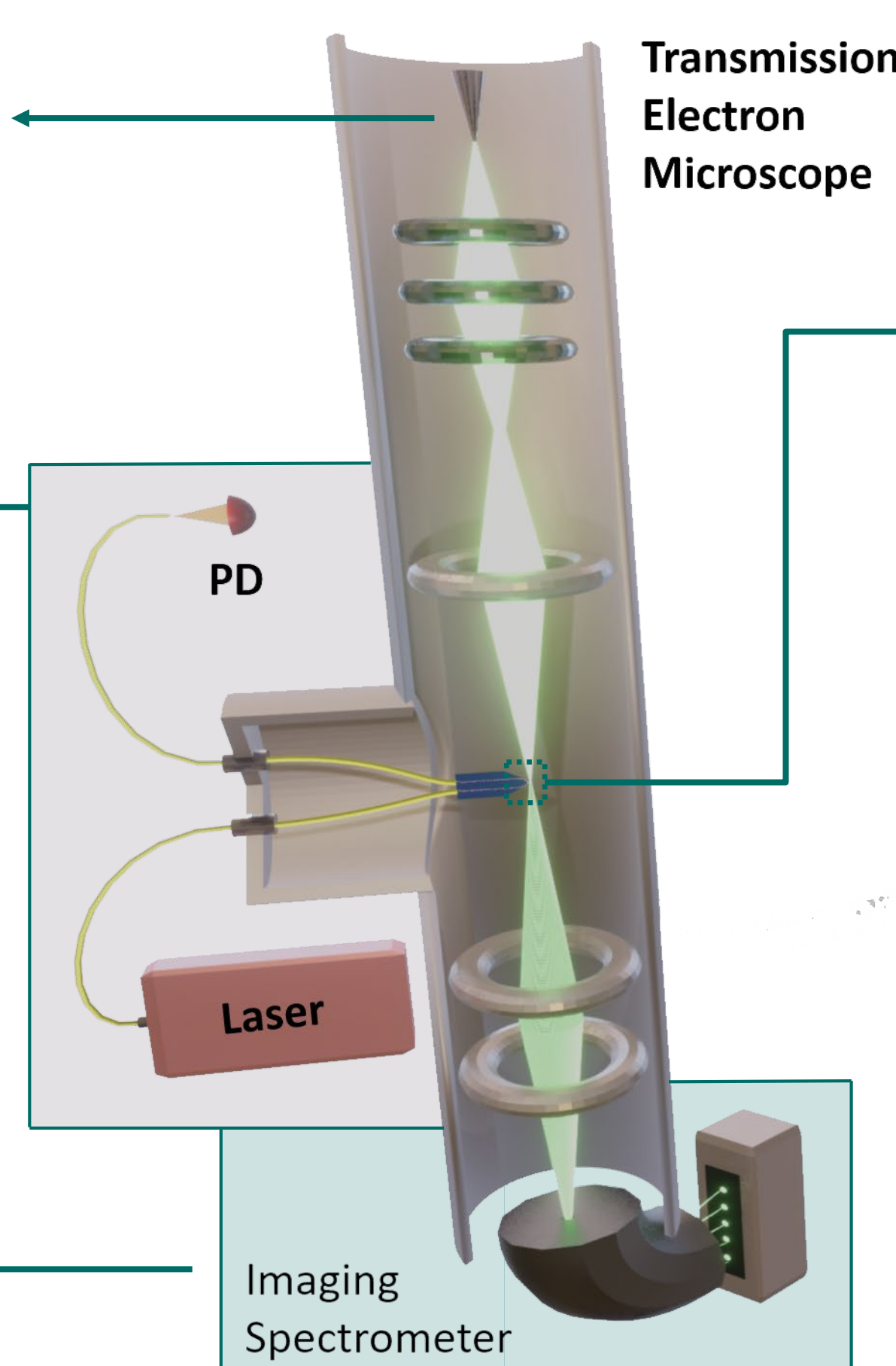
Continuous-wave optical pump setup^[5]

- Narrow line-width frequency-tunable CW fiber laser
- Control over input power and polarization
- Optical analysis of transmitted light

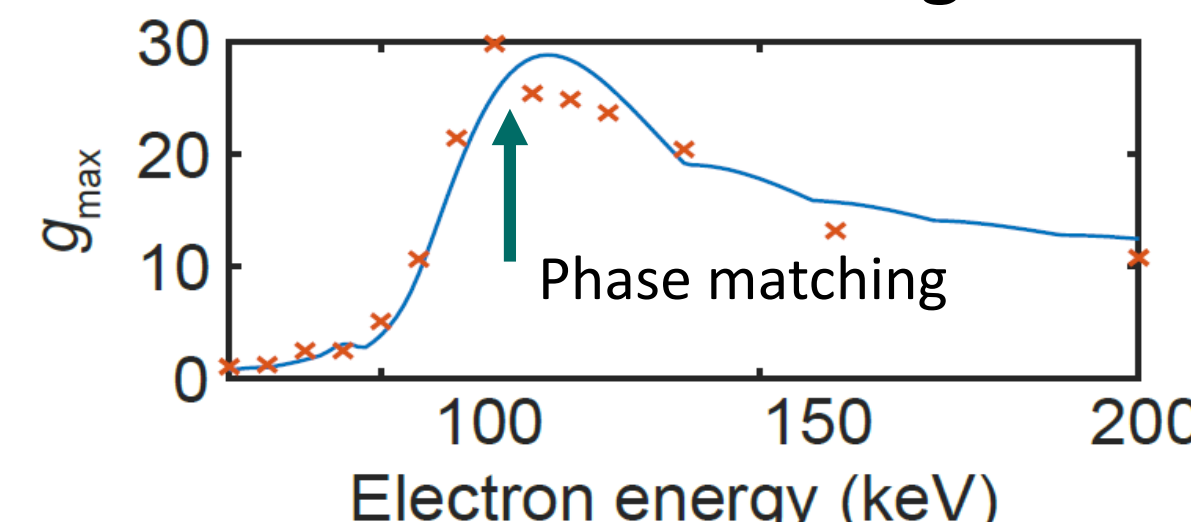
Electron energy spectra



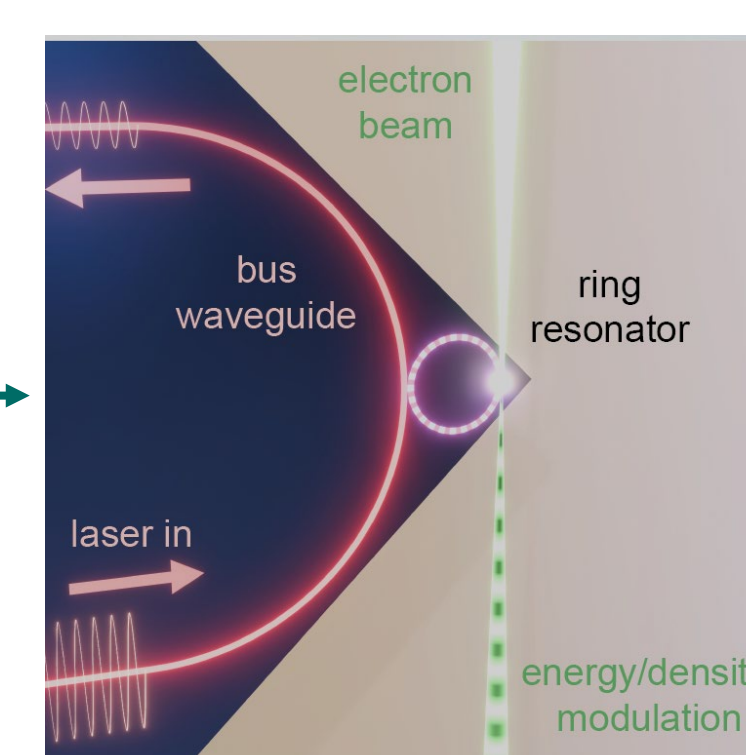
- Observe inelastic scattering for low CW input powers
- Efficient interaction



Phase Matching

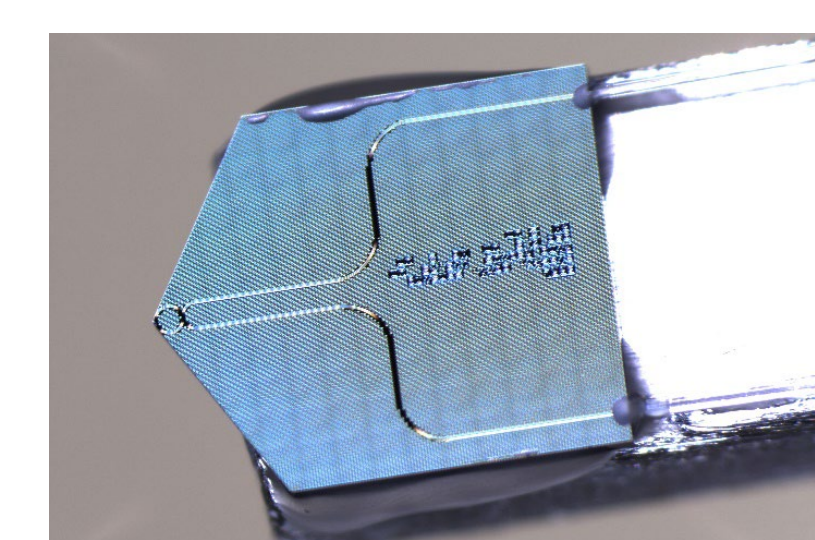


- Vary electron energy
- determine the maximum coupling



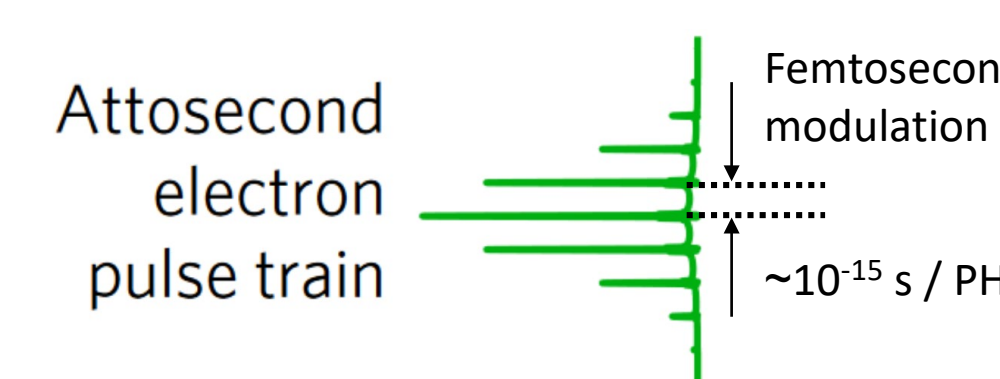
Si₃N₄ Microresonators

- Fiber-coupled, chip-based microresonators
- Top air cladding to facilitate electron-light coupling
- High internal Q factor $Q_0 \sim 0.74 \times 10^6$ at 1550nm
- Modes with strong coupling to electrons and anomalous dispersion

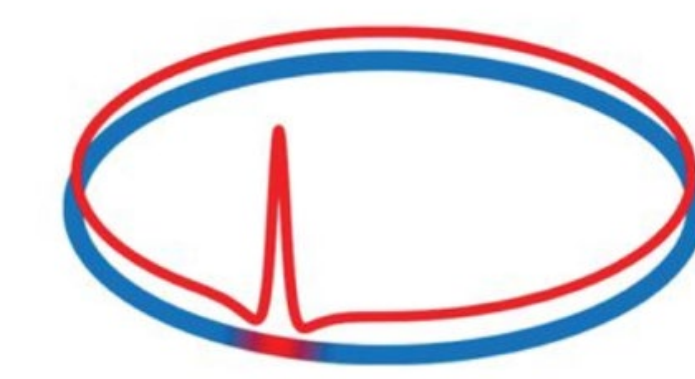
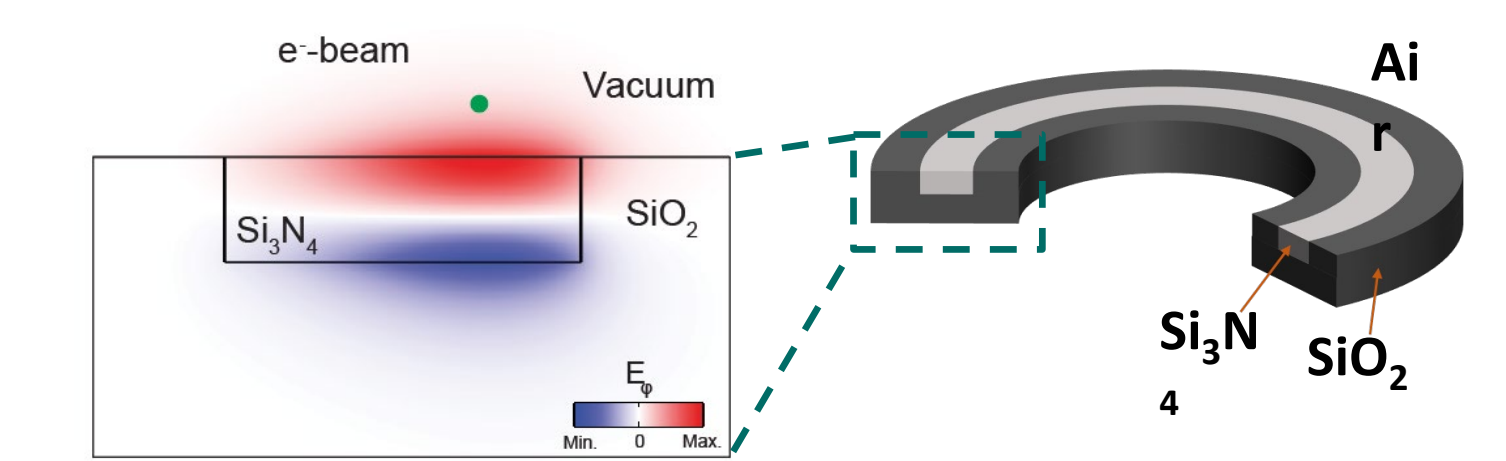


designed & fabricated by Kippenberg group and Center of MicroNanoTechnology (CMI) at EPFL^[12]

Electron Beam Modulation at GHz-PHz Frequencies

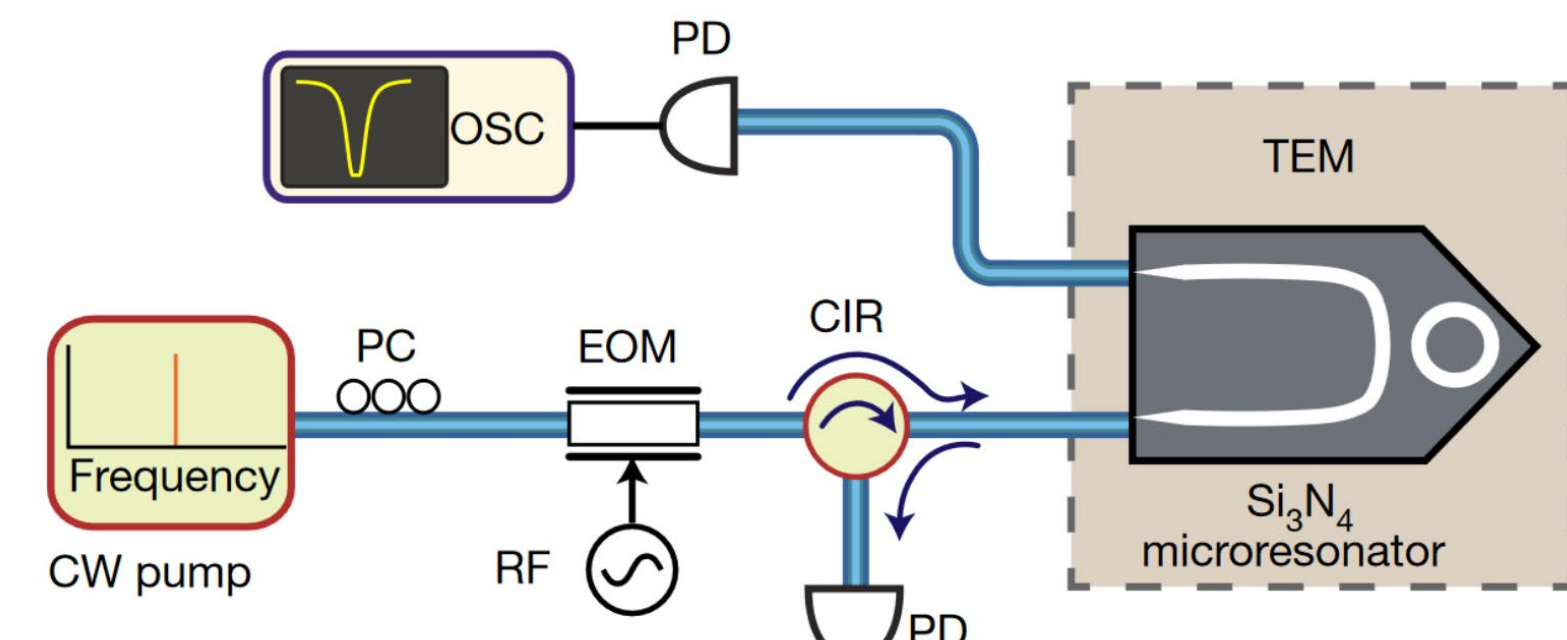


- Modulation of the electron beam at the optical frequency (PHz)^[10]
- Soliton pulses allow for deep sub-harmonic modulations (GHz-THz)^[7]



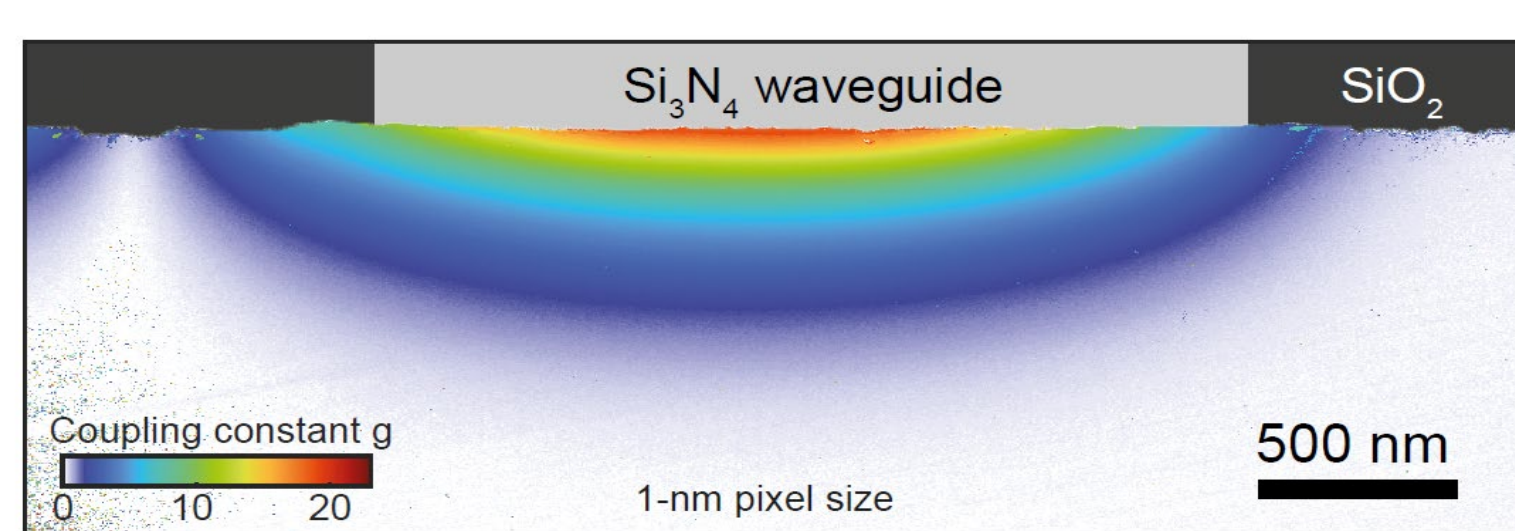
In-situ Metrology of Integrated Photonic Devices

J.-W. Henke *et al.*, *Nature* **600**, 653 (2021). & Y. Yang *et al.*, *Science* **383**, 168–173 (2024).



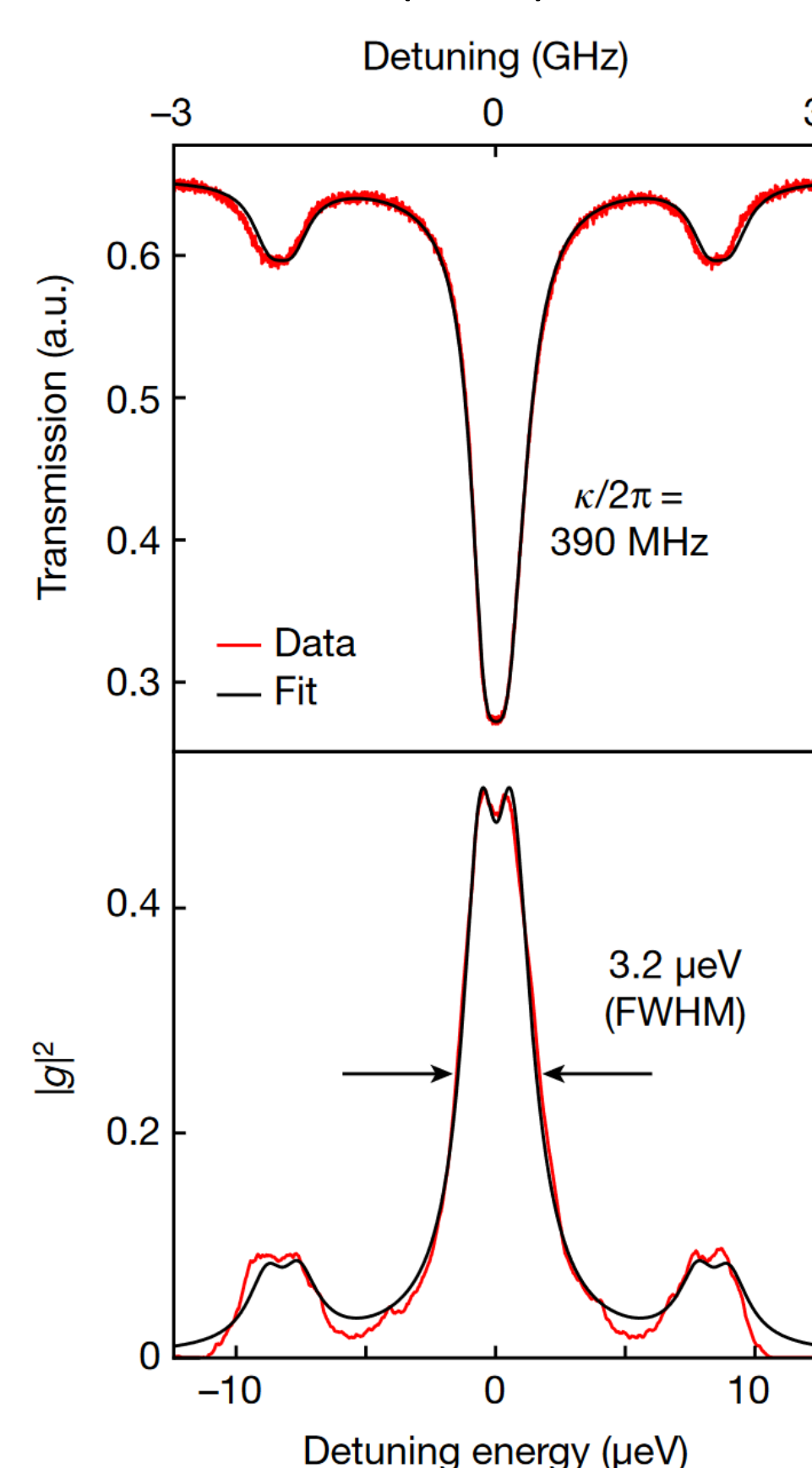
Electron energy-gain spectroscopy of a cavity mode

- optical transmission as a function of detuning
- electron energy spectra recorded with fast detector (100-μs binning)
- energy resolution (sub-neV) decoupled from ZLP width (~500 meV)
- in-situ resonator mode characterization



photon-induced near-field electron microscopy (PINEM)

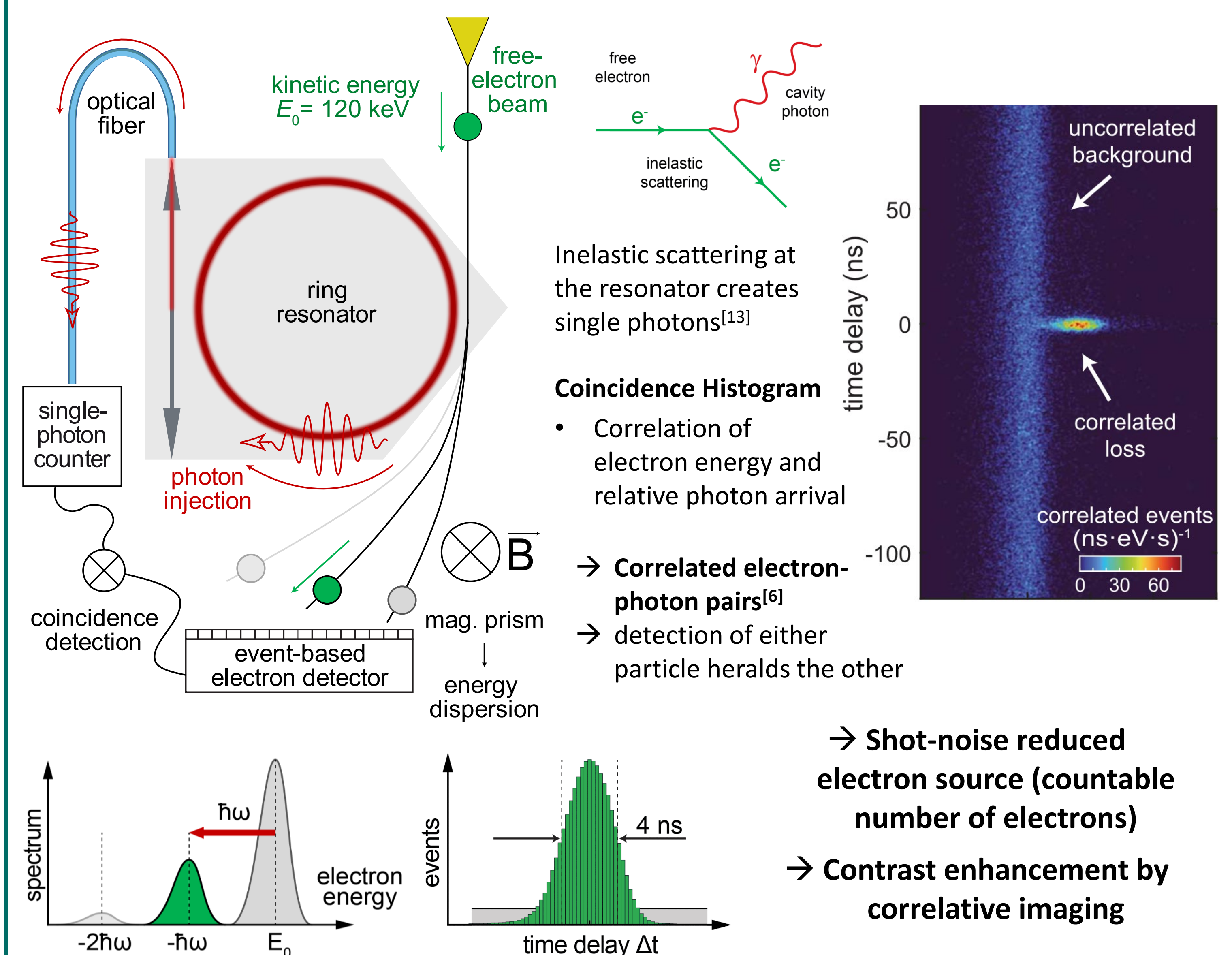
- energy-filtered image stack of individual photon sidebands
- Quantitative reconstruction of mode profile



→ combined nm-μeV spatial and spectral in-situ characterization of an integrated photonics circuit

Free-Electron Cavity-Photon Pairs & Single Particle Heralding

A. Feist *et al.*, *Science* **377**, 777 (2022).



Acknowledgments

References

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